



9/2/2009

**PRODUCT RELIABILITY REPORT
FOR**

DS3645, Rev A4

Maxim Integrated Products

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Prepared by:

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Conclusion:

The following qualification successfully meets the quality and reliability standards required of all Maxim products:

DS3645, Rev A4

In addition, Maxim's continuous reliability monitor program ensures that all outgoing product will continue to meet Maxim's quality and reliability standards. The current status of the reliability monitor program can be viewed at <http://www.maxim-ic.com/TechSupport/dsreliability.html>.

Device Description:

A description of this device can be found in the product data sheet. You can find the product data sheet at http://dbserv.maxim-ic.com/l_datasheet3.cfm.

Reliability Derating:

The Arrhenius model will be used to determine the acceleration factor for failure mechanisms that are temperature accelerated.

$$AfT = \exp((Ea/k) * (1/Tu - 1/Ts)) = tu/ts$$

AfT = Acceleration factor due to Temperature
tu = Time at use temperature (e.g. 55°C)
ts = Time at stress temperature (e.g. 125°C)
k = Boltzmann's Constant (8.617 x 10⁻⁵ eV/°K)
Tu = Temperature at Use (°K)
Ts = Temperature at Stress (°K)
Ea = Activation Energy (e.g. 0.7 ev)

The activation energy of the failure mechanism is derived from either internal studies or industry accepted standards, or activation energy of 0.7ev will be used whenever actual failure mechanisms or their activation energies are unknown. All deratings will be done from the stress ambient temperature to the use ambient temperature.

An exponential model will be used to determine the acceleration factor for failure mechanisms, which are voltage accelerated.

$$AfV = \exp(B * (Vs - Vu))$$

AfV = Acceleration factor due to Voltage
Vs = Stress Voltage (e.g. 7.0 volts)
Vu = Maximum Operating Voltage (e.g. 5.5 volts)
B = Constant related to failure mechanism type (e.g. 1.0, 2.4, 2.7, etc.)

The Constant, B, related to the failure mechanism is derived from either internal studies or industry accepted standards, or a B of 1.0 will be used whenever actual failure mechanisms or their B are unknown. All deratings will be done from the stress voltage to the maximum operating voltage. Failure rate data from the operating life test is reported using a Chi-Squared statistical model at the 60% or 90% confidence level (Cf).

The failure rate, Fr, is related to the acceleration during life test by:

$$Fr = X / (ts * AfV * AfT * N * 2)$$

X = Chi-Sq statistical upper limit
N = Life test sample size

Failure Rates are reported in FITs (Failures in Time) or MTTF (Mean Time To Failure). The FIT rate is related to MTTF by:

$$MTTF = 1/Fr$$

NOTE: MTTF is frequently used interchangeably with MTBF.

The calculated failure rate for this device/process is:

FAILURE RATE: **MTTF (YRS):** **30669** **FITS:** **3.7**
DEVICE HOURS: **246174162** **FAILS:** **0**

Only data from Operating Life or similar stresses are used for this calculation.

The parameters used to calculate this failure rate are as follows:

Cf: 60% **Ea: 0.7** **B: 0** **Tu: 25 °C** **Vu: 5.5 Volts**

The reliability data follows. At the start of this data is the device information. The next section is the detailed reliability data for each stress. The reliability data section includes the latest data available and may contain some generic data. **Bold** Product Number denotes specific product data.

Device Information:

Process: E35X-3P3M,DPE2,CrSi,DSD,PDES,D,PDRES,Cap,ENPN,DPT,HTO,SgHalo
 Passivation: TEOS Ox-Nit Passivation for E35X; Full BEOL at SA; PT only in Dallas
 Die Size: 203 x 198
 Number of Transistors: 314056
 Interconnect: Aluminum / 0.5% Copper
 Gate Oxide Thickness: 120 Å

DATA RETENTION

DESCRIPTION	DATE	CODE/PRODUCT/LOT	CONDITION	READPOIN	QTY	FAILS	FA#
STORAGE LIFE	0747	DS3655	QS709624AB 150C	1000 HRS	77	0	
STORAGE LIFE	0822	MAX17041	QJ839631BD 150C	1000 HRS	77	0	
STORAGE LIFE	0827	DS3610	QK813039AB 150C	1000 HRS	77	0	
STORAGE LIFE	0830	DS3645	QC845089A 150C	1000 HRS	77	0	
Total:						0	

ESD HBM

DESCRIPTION	DATE	CODE/PRODUCT/LOT	CONDITION	READPOIN	QTY	FAILS	FA#
ESD SENSITIVITY	0915	DS3645	QS928615BB JESD22-A114 HBM 2000 VOLTS	1 PUL'S	3	0	
ESD SENSITIVITY	0915	DS3645	QS928615BB JESD22-A114 HBM 4000 VOLTS	1 PUL'S	3	0	
ESD SENSITIVITY	0915	DS3645	QS928615BB JESD22-A114 HBM 8000 VOLTS	1 PUL'S	3	3	No FA
ESD SENSITIVITY	0915	DS3645	QS928615BB JESD22-A114 HBM 500 VOLTS	1 PUL'S	6	0	
ESD SENSITIVITY	0915	DS3645	QS928615BB JESD22-A114 HBM 1000 VOLTS	1 PUL'S	6	0	

Total: 3

LATCH-UP

DESCRIPTION	DATE	CODE/PRODUCT/LOT	CONDITION	READPOIN	QTY	FAILS	FA#
LATCH-UP V	0915	DS3645	QS928615BB JESD78A, V-SUPPLY TEST 125C		6	0	
LATCH-UP I	0915	DS3645	QS928615BB JESD78A, I-TEST 125C		6	0	
Total:					0		

OPERATING LIFE

DESCRIPTION	DATE	CODE/PRODUCT/LOT	CONDITION	READPOIN	QTY	FAILS	FA#
HIGH TEMP OP LIFE	0719	DS1091L	QJ721459AD 125C, 3.6 VOLTS	1000 HRS	45	0	
HIGH TEMP OP LIFE	0719	DS1091L	QJ721459AD 125C, 3.6 VOLTS	1000 HRS	32	0	
HIGH TEMP OP LIFE	0745	DS1099	VD736413AC 125C, 5.5 VOLTS	240 HRS	45	0	
HIGH TEMP OP LIFE	0747	DS3655	QS709624AB 125C, 3.6V (PSA) & 3.0V (PSB)	1000 HRS	45	0	
HIGH TEMP OP LIFE	0810	DS1875	QJ751639AA 125C, 5.5 VOLTS	192 HRS	77	0	
HIGH TEMP OP LIFE	0822	MAX17041	QJ839631BD 125C, 5.5V (PSA) & 9.2V (PSB)	192 HRS	45	0	
HIGH TEMP OP LIFE	0827	DS3610	QK813039AB 125C, 3.6 VOLTS	1000 HRS	45	0	
HIGH TEMP OP LIFE	0830	DS3645	QC845089A 125C, 3.6V (PSA) & 3.3V (PSB)	1000 HRS	45	0	
HIGH TEMP OP LIFE	0832	DS2776	QJ823626BC 125C, 8.4V (PSB) & 4.2V (PSA)	192 HRS	77	0	

Total: 0

FAILURE RATE: MTTF (YRS): 30669 FITS: 3.7
DEVICE HOURS: 246174162 FAILS: 0